

Product Data Sheet

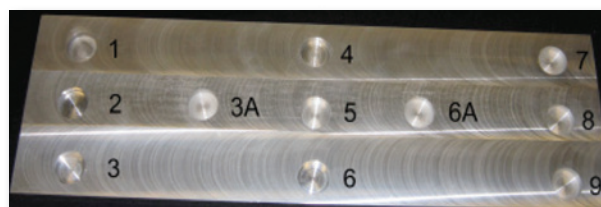
Cu/In/Ga Target (380mm x 126mm x 6mm)

Test Scope

For 11 areas of the target (as identified in the pictures on the right), 3 samples were extracted and analyzed. The three samples were from the top (1-2mm depth), middle (3-4mm depth), and bottom (5-6mm depth). Tests were performed on ICP-OES which has a standard variation of 0.12%.

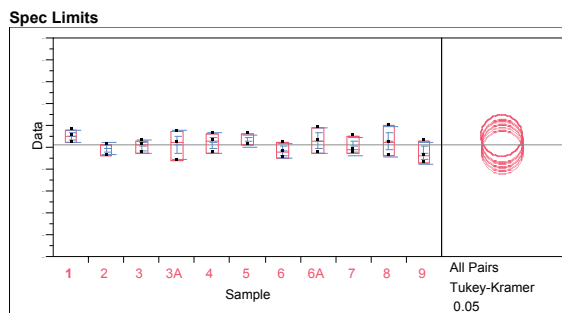


Test Target



Test Target

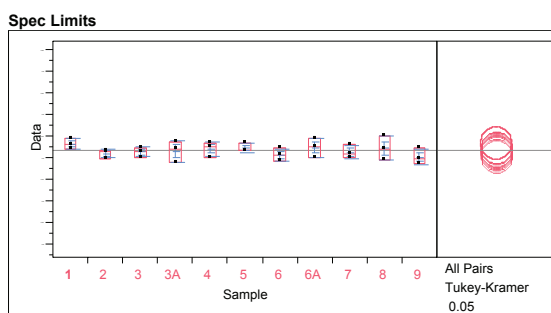
Oneway (JMP) Analysis of Data By Sample Attribute=Cu



Std Deviations

Level	Number	Std Dev
1	3	0.030000
2	3	0.028868
3	3	0.030551
3A	3	0.065574
4	3	0.045826
5	3	0.028868
6	3	0.035119
6A	3	0.060000
7	3	0.041633
8	3	0.070238
9	3	0.051316

Oneway (JMP) Analysis of Data By Sample Attribute=CuII



Std Deviations

Level	Number	Std Dev
1	3	0.001212
2	3	0.000994
3	3	0.001128
3A	3	0.002505
4	3	0.001700
5	3	0.001068
6	3	0.001448
6A	3	0.002283
7	3	0.001550
8	3	0.002757
9	3	0.001833

OVER→

Form No. 98571 R0

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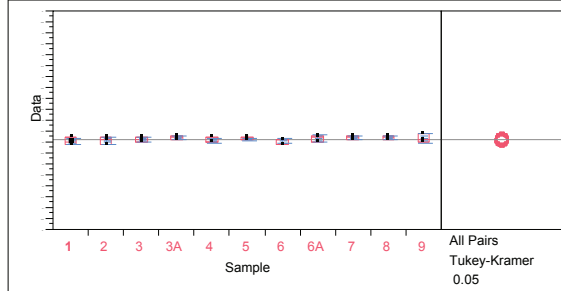


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Cu/In/Ga Target (380mm x 126mm x 6mm)

Oneway (JMP) Analysis of Data By Sample Attribute=GA

Spec Limits

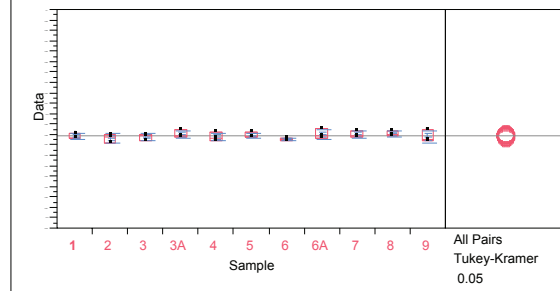


Std Deviations

Level	Number	Std Dev
1	3	0.015275
2	3	0.015275
3	3	0.010000
3A	3	0.010000
4	3	0.011547
5	3	0.005774
6	3	0.011547
6A	3	0.015275
7	3	0.010000
8	3	0.010000
9	3	0.020817

Oneway (JMP) Analysis of Data By Sample Attribute=Gall

Spec Limits

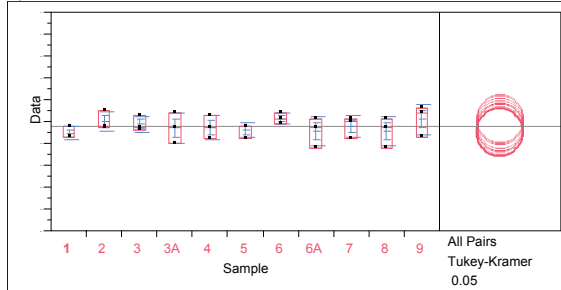


Std Deviations

Level	Number	Std Dev
1	3	0.000298
2	3	0.000426
3	3	0.000302
3A	3	0.000393
4	3	0.000397
5	3	0.000236
6	3	0.000125
6A	3	0.000456
7	3	0.000348
8	3	0.000271
9	3	0.000616

Oneway (JMP) Analysis of Data By Sample Attribute=In

Spec Limits



Std Deviations

Level	Number	Std Dev
1	3	0.028868
2	3	0.043589
3	3	0.037859
3A	3	0.070000
4	3	0.055076
5	3	0.034641
6	3	0.025166
6A	3	0.066583
7	3	0.049329
8	3	0.066583
9	3	0.070000

Summary

The statistical equivalence of all the preceding test data (for Cu/In Ratio, Gall Ratio, Cu wt %, In wt %, Ga wt %) suggest that the material uniformity of the target is very high. The major contributor to the minimal variation shown within the test data is the inherent variation induced by the test equipment.

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